Mineral

Powder Diffraction File Data Book & Search Manual

850 new patterns

3400 patterns total 2700 species

Data Book

- Enlarged and revised for Sets 1-35
- Ordered alphabetically on mineral name

Search Manual contains sections on

- Chemical Name
- Hanawalt Numerical
- Fink Numerical
- Mineral Name

Since its inception almost 50 years ago, the Powder Diffraction File has always been well served in the area of mineral species. In 1974 the first special mineral based publication was produced, this being in the form of a book of minerals containing about 2,600 selected patterns in numerical sequence. A supplement to this edition was produced in 1981. In 1980 an alphabetically ordered data book was produced followed by a group data book in 1983. Each of these products has proven very popular both with the community of mineralogists as well as others involved in general qualitative phase identification.

The International Centre for Diffraction Data is now pleased to announce a new Mineral Powder Diffraction File containing about 2,700 species represented by 3,400 patterns. This selection includes about 850 new patterns added since 1980. This revision of the mineral file has been produced by the Editors of the International Centre for Diffraction Data in cooperation with the Minerals Subcommittee, and has been further guided by nomenclature recommendations of the International Mineralogical Association.

The Mineral Powder Diffraction File Data Book is ordered alphabetically on mineral name, thus grouping together patterns of the same mineral including hydrates, polytypes, order-disorder and chemical varieties, and obviating the need for an index. All data have been reedited with special reference to nomenclature, chemical formula, indexing and other crystallographic data. Physical data is also recorded including opaque optical data where available.

The Search Manual supplied with the new Data Book is based on the latest Hanawalt search/matching techniques including special provisions for finding patterns recorded using the Debye-Scherrer technique and data from highly oriented materials.

We feel that with the large number of new patterns, along with the improved quality of many of the older data, this new product should prove invaluable to both existing users of the Mineral Data products as well as to those new to the field.

Price: \$550.00 Terms: Domestic – 30 days net Foreign – Prepayment in U.S. currency

Please address all inquires and orders to: JCPDS—International Centre for Diffraction Data 1601 Park Lane Swarthmore, Pennsylvania 19081 U.S.A. Telephone: (215) 328–9400



Set 371987-1988

Powder Diffraction File

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- 150 Replacements
- 32 New NBS
- 83 New Minerals
- 231 New Metals & Alloys
- 34 New Common Phases
- New Inorganics & Organics
- NBS*AIDS83 Review

New:

- CD-ROM
- Set 37 Data Book
- Sets 29-30 Book Form
- Methods & Practices in X-Ray Powder Diffraction

For further information contact: JCPDS International Centre for Diffraction Data 1606 Park Lane, Swarthmore, PA 19081 USA (215) 328-9400 Telex: 847170



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Powder Diffraction File 29-30

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Crystallographic data evaluation made using NBS*AIDS83. Figure of merit for completeness and accuracy of interplanar spacings is assigned to each indexed pattern.

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